

Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 295880US2PCT	SERIAL NO. 10/591,433			
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Mikio IZUMI, et al.				
		FILING DATE September 1, 2006	GROUP 2108			
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA					
	AB					
	AC					
	AD					
	AE					
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	AH					
	AI					
	AJ					
	AK					
	AL					
	AM					
	AN					
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
/DC/	AO	WO 00/41101	07/13/2000	WIPO		
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	AR					
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Examiner /Dwin Craig/ (07/15/2009)				Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /DC/ (07/15/2009)